	Application No.	Applicant(s)
Notice of Allowability	10/706,615	MAERITZ, JORN
	Examiner	Art Unit
	Zoila E. Cabrera	2125
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT IS of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED in 5) or other appropriate common RIGHTS. This application is a	n this application. If not included unication will be mailed in due course. THIS
1. This communication is responsive to <u>1/31/05</u> .		
2. The allowed claim(s) is/are <u>1-5</u> .		
3. $\boxtimes$ The drawings filed on <u>28 June 2004</u> are accepted by the	Examiner.	
<ul> <li>4.  Acknowledgment is made of a claim for foreign priority to a)  All b)  Some* c)  None of the:</li> <li>1.  Certified copies of the priority documents have</li> <li>2.  Certified copies of the priority documents have</li> <li>3.  Copies of the certified copies of the priority documents have linternational Bureau (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> </ul>	ve been received. ve been received in Applicatio	on No
Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	" of this communication to file MENT of this application.	e a reply complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be subr INFORMAL PATENT APPLICATION (PTO-152) which give	mitted. Note the attached EXA ves reason(s) why the oath or	AMINER'S AMENDMENT or NOTICE OF r declaration is deficient.
<ol> <li>CORRECTED DRAWINGS ( as "replacement sheets") mu         <ul> <li>(a)  including changes required by the Notice of Draftsper</li> <li>1)  hereto or 2)  to Paper No./Mail Date</li> <li>(b)  including changes required by the attached Examiner Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in</li> </ul> </li> <li>DEPOSIT OF and/or INFORMATION about the dependence of the paper of the p</li></ol>	rson's Patent Drawing Review   r's Amendment / Comment or  1.84(c)) should be written on the header according to 37 CF  osit of BIOLOGICAL MATI	r in the Office action of the drawings in the front (not the back) of R 1.121(d). ERIAL must be submitted. Note the
	FOR THE DEPOSIT OF BIC	JLOGICAL MATERIAL.
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. ☐ Notice of In	formal Patent Application (PTO-152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview S	ummary (PTO-413).
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/	Paper No./ (08), 7. ⊠ Examiner's	Mail Date Amendment/Comment
Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit	8 M Evaminada	Statement of Reasons for Allowance
of Biological Material	9. ☐ Other	

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## **DETAILED ACTION**

## **EXAMINER'S AMENDMENT**

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows:

Claim 5, line 14, after "process" delete - - on --.

## Allowable Subject Matter

2. Claims 1-5 are allowed.

The following is an examiner's statement of reasons for allowance: The allowability of the claims resides, at least in part, that the closest prior art of record

Miller (US 6,556,884) does not disclose or suggest, alone or in combination the step of:

Regarding independent claim 1, marking at least one of the processed wafers according to a deterministic selection criterion based on requirements of the runto-run method and an inline SPC method, and selecting at least one wafer necessary for the run-to-run method and also for the inline SPC method according to the deterministic selection criterion, in combination with the other elements and features of the claimed invention.

As for independent claim 3, marking at least one of the plurality of wafers according to a deterministic selection criterion based on the run-to-run method and an inline SPC method, and selecting at least one wafer for the run-to-run

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method and the inline SPC method according to the deterministic selection criterion, in combination with the other elements and features of the claimed invention.

As for independent claim 4, marking at least one of the processed wafers according to a deterministic selection criterion based on the run-to-run method and an inline SPC method, and selecting at least one wafer for the run-to-run method and the inline SPC method according to the deterministic selection criterion, in combination with the other elements and features of the claimed invention.

As for independent claim 5, marking at least one of the processed wafers according to a deterministic selection criterion based on the run-to-run method and an inline SPC method, and selecting at least one wafer for the run-to-run method and the inline SPC method according to the deterministic selection criterion, in combination with the other elements and features of the claimed invention.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Zoila E. Cabrera whose telephone number is 571-272-3738. The examiner can normally be reached on M-F from 8:00 a.m. to 5:30 p.m. EST (every other Friday).

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo Picard, can be reached on (571) 2723749. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306. Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-305-9600.

Zoila Cabrera Patent Examiner March 3, 2005

LEO PICARD
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2100

LP.P